

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 230421US26YA		SERIAL NO. 10/673,501	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Andrej S. MITROVIC			
				FILING DATE September 30, 2003		GROUP 2128	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/A.S./	AA	US 2005-0071037	3/31/2005	Strang			
	AB	US 2005-0071035	3/31/2005	Strang			
	AC	US 2005-0071038	3/31/2005	Strang			
	AD	US 2005-0071036	3/31/2005	Mitrovic			
	AE	US 2005-0071039	3/31/2005	Mitrovic			
	AF	US 6,198,980 B1	3/2001	Costanza, John R.			
	AG	US 7,107,571 B2	9/2006	Chang, et al.			
	AH	US 5,741,070	4/21/1998	Mehrdad Mahmud Moslehi			
	AI	US 2004/0058255 A1	3/25/2004	Scott Jessen, et al			
	AJ	US 5,539,652	7/23/1996	Tegethoff			
	AK	US 6,581,029 B1	6/17/2003	Fisher			
	AL	US 2003/0003607	1/2/2003	Kagoshima et al			
	AM	US 6,529,789	3/2003	Campbell, et al.			
/A.S./	AN	US 5,377,116	12/1994	Wayne, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	CN 1335558A	2/13/2002	China (with Partial English Translation)	X		
/A.S./	AP	WO 02/07210 A2	1/24/2002	WIPO			X
	AQ	EP 0 718 595 A2	6/26/1996	EUROPE			X
/A.S./	AR	JP 2004-527117	9/2/2004	Japan (Corresponding to WO 02/077589 A2 and A3)			X
	AS	WO 03/060779 A1	7/24/2003	WIPO			X
	AT	JP 2005-515623	5/26/2005	JAPAN (With English Abstract)			X
	AU	WO 03/009345 A2	1/30/2003	WIPO			X
/A.S./	AV	JP 2005-522018	7/21/2005	JAPAN (With English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Naomi YONEMURA, et al. "Heat Analysis on Insulated Metal Substrates", 1996, IEEE, pgs. 1407-1410					
/A.S./	AX	Heru SETYAWAN, et al. "Visualization and numerical simulation of fine particle transport in a low-pressure parallel plate chemical vapor deposition reactor", Chemical Engineering Science 57 (2002) pages 497-506					
	AY						
	AZ						
Examiner /Akash Saxena/ (12/15/2010)					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 12/15/2010		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
<div style="font-size: 2em;">↓</div>	AAA	US 5,629,877	5/1997	Tamegaya, Yukio			
	AAB	US 6,625,497	9/2003	Fairbairn, et al.			
	AAC	US 6,185,472	2/6/2001	Onga, et al.			
	AAD	US 7,047,095 B2	5/16/2006	Tomoyasu			
	AAE	US 6,587,744 B1	7/1/2003	Stoddard, et al.			
	AAF						
	AAG						
	AAH						
	AAI						
	AAJ						
	AAK						
	AAL						
	AAM						
	AAN						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION			
				YES	NO		
<div style="font-size: 2em;">↓</div>	AAO	JP 2003-17471	1/17/2003	JAPAN (With English Abstract)		X	
	AAP	WO 02/065511 A2	8/22/2002	WIPO		X	
	AAQ	JP 2004-524685	8/12/2004	JAPAN (Corresponding to WO 02/065511 A2 and A3)		X	
	AAR	WO 02/069063 A2	9/6/2002	WIPO		X	
	AAS	JP 2004-531878A	10/14/2004	JAPAN (Corresponding to WO 02/069063 A2 and A3)		X	
	AAT	JP 2000-517473	12/26/2000	JAPAN (With English Abstract)		X	
	AAU	WO 03/058699 A1	7/17/2003	WIPO		X	
	AAV	JP 2005-514790	5/19/2005	JAPAN (With English Abstract)		X	
	OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)						
	AAW						
	AAX						
	AAY						
	AAZ						
						<input type="checkbox"/> Additional References sheet(s) attached	
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	AAAA						
	AAAB						
	AAAC						
	AAAD						
	AAAE						
	AAAF						
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	AAAH						
	AAAI						
	AAAJ						
	AAAK						
	AAAL						
	AAAM						
	AAAN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/A.S./	AAAO	JP 2002-367875	12/20/2002	JAPAN (with English Abstract and Computer generated translation only)		X	
↓	AAAP	JP 2003-502771	1/21/2003	JAPAN (with English Abstract and Computer generated translation only)	X		
↓	AAAQ	WO 02/077589 A2	10/3/2002	WIPO		X	
↓	AAAR	WO 97/21244	12/6/1997	WIPO		X	
/A.S./	AAAS	JP 11-176906	7/2/1999	JAPAN (with English Abstract and Computer generated translation only)	X		
	AAAT						
	AAAU						
	AAAV						
	AAAW						
	AAAX						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AAAY						
	AAAZ						
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